

<b>Notice of References Cited</b>		Application/Control No. 09/970,087	Applicant(s)/Patent Under Reexamination PISHARODY ET AL.	
		Examiner Jeffrey Fredman	Art Unit 1634	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0203394	10-2003	Eichen et al.	435/6
	B	US-5,965,452	10-1999	Kovacs, Gregory T. A.	436/149
	C	US-6,127,127	10-2000	Eckhardt et al.	435/6
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Ueda et al, "Atomic force microscopy observation of deoxyribonucleic acid stretched and anchored onto aluminum electrodes", Japanese J. Appl. Phys. (1999) 38(4A):2118-2119.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.